



NSAI
Standards

Irish Standard
I.S. EN 61967-8:2011

Integrated circuits - Measurement of electromagnetic emissions -- Part 8: Measurement of radiated emissions - IC stripline method (IEC 61967-8:2011 (EQV))

I.S. EN 61967-8:2011

Incorporating amendments/corrigenda issued since publication:

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EUROPEAN STANDARD
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EN 61967-8

October 2011

ICS 31.200

English version

**Integrated circuits -
Measurement of electromagnetic emissions -
Part 8: Measurement of radiated emissions -
IC stripline method
(IEC 61967-8:2011)**

Circuits intégrés -
Mesure des émissions
électromagnétiques -
Partie 8: Mesure des émissions
rayonnées -
Méthode de la ligne TEM à plaques
(stripline) pour CI
(CEI 61967-8:2011)

Integrierte Schaltungen -
Messung von elektromagnetischen
Aussendungen -
Teil 8: Messung der abgestrahlten
Aussendungen -
IC-Streifenleiterverfahren
(IEC 61967-8:2011)

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CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Management Centre: Avenue Marnix 17, B - 1000 Brussels

I.S. EN 61967-8:2011

EN 61967-8:2011

- 2 -

Foreword

The text of document 47A/868/FDIS, future edition 1 of IEC 61967-8, prepared by SC 47A, "Integrated circuits", of IEC TC 47, "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 61967-8:2011.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2012-06-15
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2014-09-15

This standard is to be used in conjunction with EN 61967-1.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CENELEC [and/or CEN] shall not be held responsible for identifying any or all such patent rights.

Endorsement notice

The text of the International Standard IEC 61967-8:2011 was approved by CENELEC as a European Standard without any modification.

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60050-131	-	International Electrotechnical Vocabulary (IEV) - Part 131: Circuit theory	-	-
IEC 60050-161	-	International Electrotechnical Vocabulary (IEV) - Chapter 161: Electromagnetic compatibility	-	-
IEC 61000-4-20	-	Electromagnetic compatibility (EMC) - Part 4-20: Testing and measurement techniques - Emission and immunity testing in transverse electromagnetic (TEM) waveguides	EN 61000-4-20	-
IEC 61967-1	-	Integrated circuits - Measurement of electromagnetic emissions, 150 kHz to 1 GHz - Part 1: General conditions and definitions	EN 61967-1	-
IEC 61967-2	-	Integrated circuits - Measurement of electromagnetic emissions, 150 kHz to 1 GHz - Part 2: Measurement of radiated emissions - TEM cell and wideband TEM cell method	EN 61967-2	-

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CONTENTS

FOREWORD.....	3
1 Scope.....	5
2 Normative references	5
3 Terms and definitions	5
4 General	6
5 Test conditions	6
5.1 General	6
5.2 Supply voltage.....	6
5.3 Frequency range	6
6 Test equipment.....	7
6.1 General	7
6.2 RF measuring instrument	7
6.3 Preamplifier.....	7
6.4 IC stripline.....	7
6.5 50 Ω termination.....	7
6.6 System gain	7
7 Test set-up	8
7.1 General	8
7.2 Test configuration.....	8
7.3 EMC test board (PCB).....	8
8 Test procedure	9
8.1 General	9
8.2 Ambient conditions	9
8.3 Operational check	9
8.4 Verification of IC stripline RF characteristic	9
8.5 Test technique.....	9
9 Test report.....	10
9.1 General	10
9.2 Measurement conditions.....	10
10 IC Emissions reference levels.....	10
Annex A (normative) IC stripline description.....	11
Annex B (informative) Specification of emission levels.....	15
Bibliography.....	17
Figure 1 – IC stripline test set-up	8
Figure A.1 – Cross section view of an example of an unshielded IC stripline.....	11
Figure A.2 – Cross section view of an example of an IC stripline with housing	12
Figure A.3 – Example of IC stripline with housing	14
Figure B.1 – Emission characterization levels	16
Table A.1 – Maximum DUT dimensions for 6,7 mm IC stripline open version	12
Table A.2 – Maximum DUT dimensions for 6,7 mm IC stripline closed version	12

INTERNATIONAL ELECTROTECHNICAL COMMISSION

INTEGRATED CIRCUITS – MEASUREMENT OF ELECTROMAGNETIC EMISSIONS –

Part 8: Measurement of radiated emissions – IC stripline method

FOREWORD

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International Standard IEC 61967-8 has been prepared by subcommittee 47A: Integrated circuits, of IEC technical committee 47: Semiconductor devices.

The text of this standard is based on the following documents:

FDIS	Report on voting
47A/868/FDIS	47A/870/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

This part of IEC 61967 is to be read in conjunction with IEC 61967-1.

A list of all parts of IEC 6xxxx series, under the general title *Integrated circuits – Measurement of electromagnetic emissions* can be found on the IEC website.

NOTE Future standards in this series will carry the new general title as cited above. Titles of existing standards in this series will be updated at the time of the next edition.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

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- replaced by a revised edition, or
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